

DATA SHEET

Model MUS154805

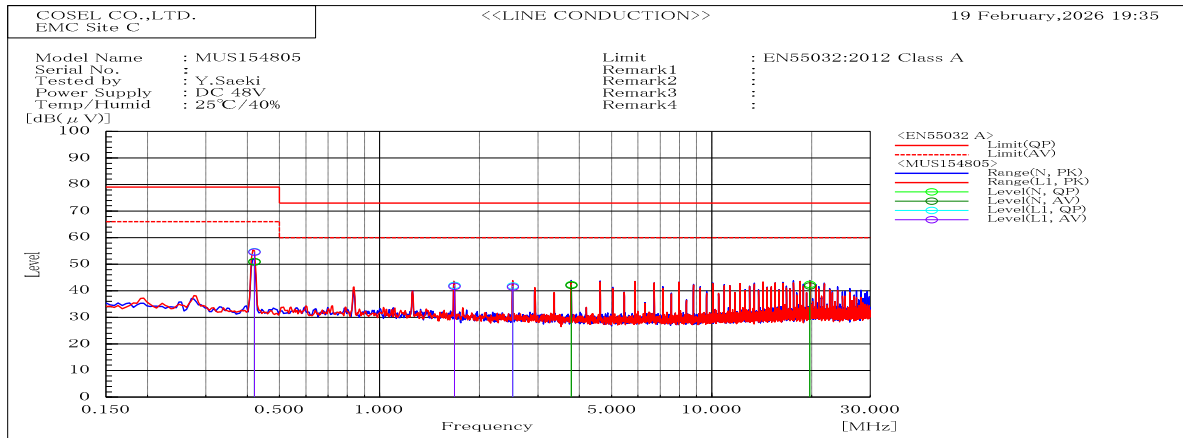
Date 15-May-26

Test EMI
Line conduction & Radiated emission

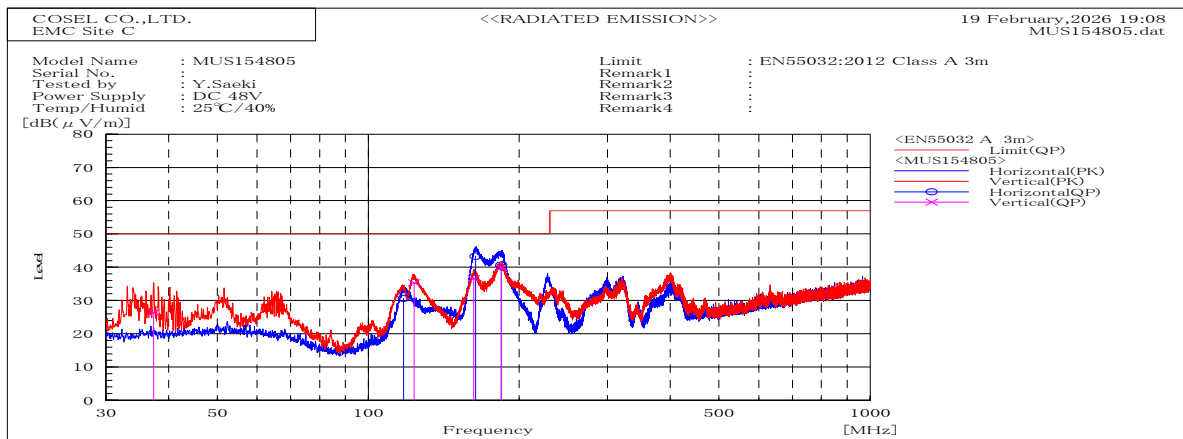
Temp. 25 degreeC

Humid. 40 %RH

Tested by Y.Saeki



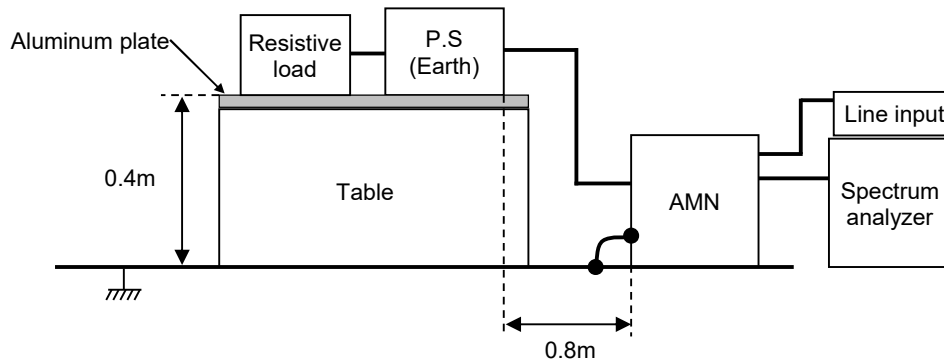
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.42	N	51	50.9	79	66	28	15.1	Pass	
3.781	N	42.4	42.1	73	60	30.6	17.9	Pass	
19.747	N	42.4	41.8	73	60	30.6	18.2	Pass	
0.42	L1	54.7	54.6	79	66	24.3	11.4	Pass	
1.68	L1	42	41.7	73	60	31	18.3	Pass	
2.52	L1	41.8	41.5	73	60	31.2	18.5	Pass	



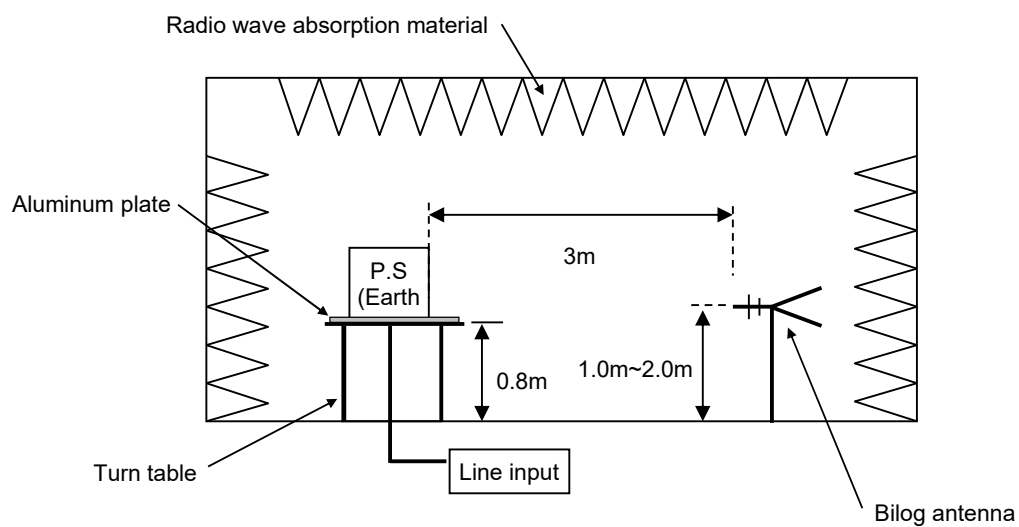
Frequency	Polarization	Stability	Level		Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)		dB(μV/m)	dB				
			QP	AV	QP	QP		cm	deg	
117.638	H	Stable	30.6	50	19.4	Pass	170	0		
163.516	H	Stable	43.3	50	6.7	Pass	189.7	357.3		
183.949	H	Stable	40.6	50	9.4	Pass	199.7	0		
37.362	V	Stable	26.4	50	23.6	Pass	100	84.1		
123.393	V	Stable	35.3	50	14.7	Pass	121.8	272.2		
162.083	V	Stable	36.6	50	13.4	Pass	101.9	263.4		
184.351	V	Stable	39.9	50	10.1	Pass	100.3	29.4		

DATA SHEET		Date	15-May-26
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Saeki

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name: MUS15□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

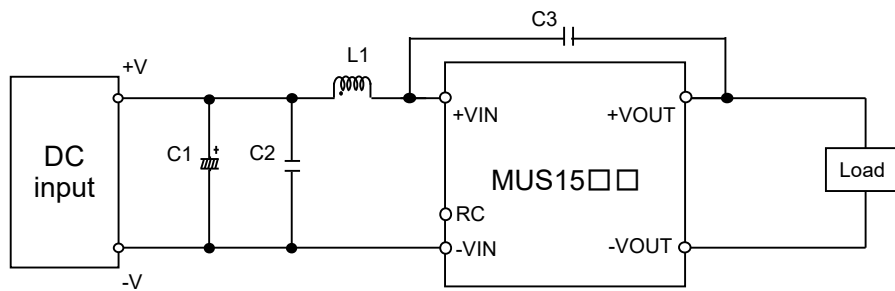


Fig.1 MUS15□□ Testing circuitry

C1 :	MUS1524□	50V 47 μ F Electric capacitor (UPWseries NICHICON)
	MUS1548□	-
C2 :	MUS1524□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1548□	100V 2.2 μ F Ceramic capacitor (C3216X7S2A225KT TDK)
C3 :	MUS15□□	2000V 1000pF Ceramic capacitor (C3225X7S3D102K200AA TDK)
L1 :	MUS1524□	1600mA 22 μ H Inductor (LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1548□	1100mA 47 μ H Inductor (LQH5BPN470M38 MURATA MANUFACTURING)